IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

βptication Serial No.10/803,264 Filing DateMarch 17, 2004 Confirmation No......5382 Inventor......Warren M. Farnworth et al. AssigneeMicron Technology, Inc. Group Art Unit......2829 Examiner Russell M. Kobert Attorney's Docket No. MI22-2524 Customer No.021567 Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and

Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

RESPONSE TO JULY 8, 2005 OFFICE ACTION

To:

Mail Stop Amendment

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

From:

D. Brent Kenady

Tel. 509-624-4276; Fax 509-838-3424

Wells St. John P.S.

601 W. First Avenue, Suite 1300 Spokane, WA 99201-3817

Responsive to the July 8, 2005 Office Action, Applicant amends and remarks as

follows:

AMENDMENTS

<u>Underlines</u> indicate insertions and strikeouts indicate deletions.

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